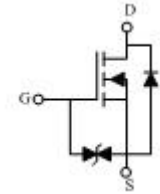
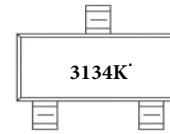
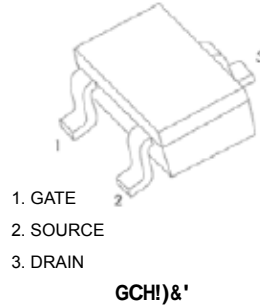


AU]b'DfcX i Wh'7 \UfUWhYf]gh]Wg`

Jf6F!8GG`	20V
R_{DS(on)}MAX	380 mΩ@4.5V
	450 mΩ@2.5V
	800 mΩ@1.8V
=8`	0.75A



: YUh i fYg'UbX' 6YbYZ]hg`

- Advanced MOSFET process technology
- Ideal for DC-DC converter, power management in portable battery, computer, printer, cellular and general purpose applications
- Low on-resistance with low gate charge
- Fast switching and reverse body recovery



8YgWf]dh]cb`

The SSF3134K utilizes the latest processing techniques to achieve high cell density and low on-resistance. These features make this device extremely efficient and reliable for use in DC-DC converter, power management in portable battery, computer, printer, cellular and general purpose applications.

5Vgc` ihY`AU]a i a`FUh]b [g (T_A=25°C unless otherwise specified)

DUfU a YhYf`	Gma Vc`	JU` i Y`	I b]h`
Drain-Source voltage	V _{DSS}	20	V
Typical Gate-Source Voltage	V _{GS}	±12	
Drain Current-Continuous	I _D	0.75	A
Drain Current -Pulsed (note1)	I _{DM}	3	
Power Dissipation (note 2)	P _D	150	mW
Thermal Resistance from Junction to Ambient	R _{θJA}	833	°C/W
Storage Temperature	T _j	150	°C
Junction Temperature	T _{stg}	-55 to +150	



9`YWhf]WU`7 \UfUWhYf]gh]Wg' ($T_A=25^\circ\text{C}$ unless otherwise specified)

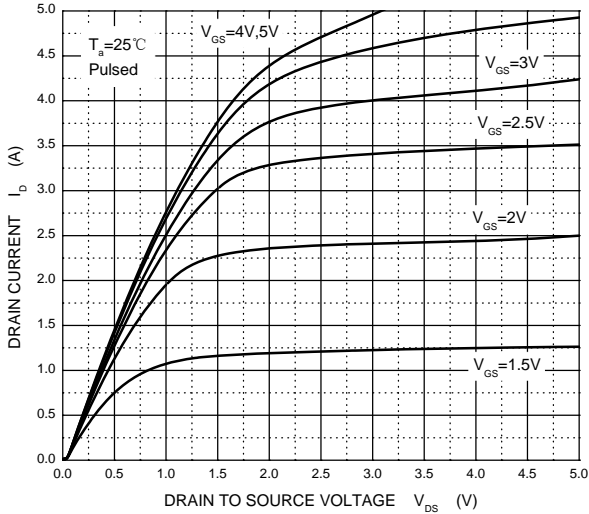
DUfU a YhYf	Gma Vc`	HYgh'7cbX]h]cb	A]b	Hmd	AUI	I b]h
Cb#CZ' GhUhYg						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	20			V
Gate-Threshold Voltage (note 3)	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	0.35		1.1	
Gate-Body Leakage Current	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 10V$			± 20	μA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20V, V_{GS} = 0V$			1	μA
Drain-Source On-State Resistance(note 3)	$R_{DS(on)}$	$V_{GS} = 4.5V, I_D = 650mA$			380	m Ω
		$V_{GS} = 2.5V, I_D = 550mA$			450	
		$V_{GS} = 1.8V, I_D = 450mA$			800	
Forward Transconductance	g_{fs}	$V_{DS} = 10V, I_D = 800mA$	1			S
8mbU a]W'7 \UfUWhYf]gh]Wg'						
Input Capacitance	C_{iss}	$V_{DS} = 16V, V_{GS} = 0V, f = 1MHz$			120	pF
Output Capacitance	C_{oss}				20	
Reverse Transfer Capacitance	C_{rss}				15	
Gk]hW\]b[`H]a Yg`						
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 10V, I_D = 500mA,$ $V_{GS} = 4.5V, R_G = 10\Omega$		6.7		ns
Rise Time	t_r			4.8		
Turn-Off Delay Time	$t_{d(off)}$			17.3		
Fall Time	t_f			7.4		
8fU]b!Gc i fWY'8]cXY'7 \UfUWhYf]gh]Wg						
Drain-Source Diode Forward Voltage (note 3)	V_{SD}	$I_S = 0.15A, V_{GS} = 0V$			1.2	V

BchYg.'

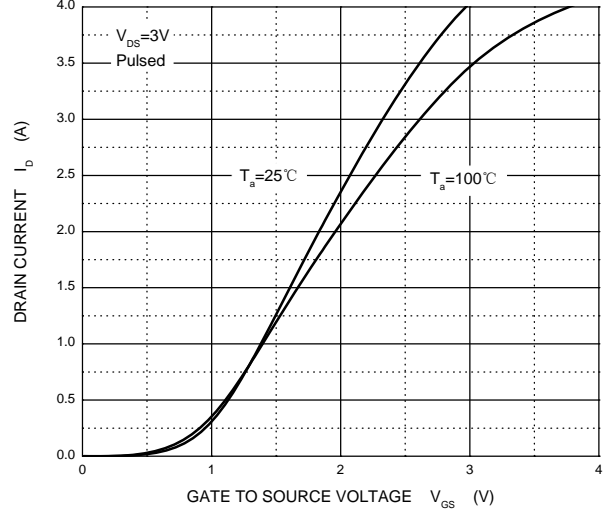
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. This test is performed with no heat sink at $T_a=25^\circ\text{C}$.
3. Pulse Test : Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 0.5\%$.

HmdjWU`9`YWhfjWU`UbX`H\Yf a U`7\UfUWhYf]ghjWg`

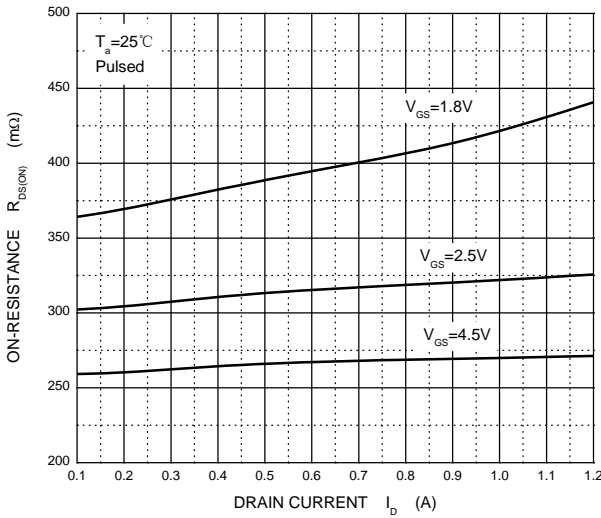
C i h d i h ' 7 \ U f U W h Y f] g h j W g



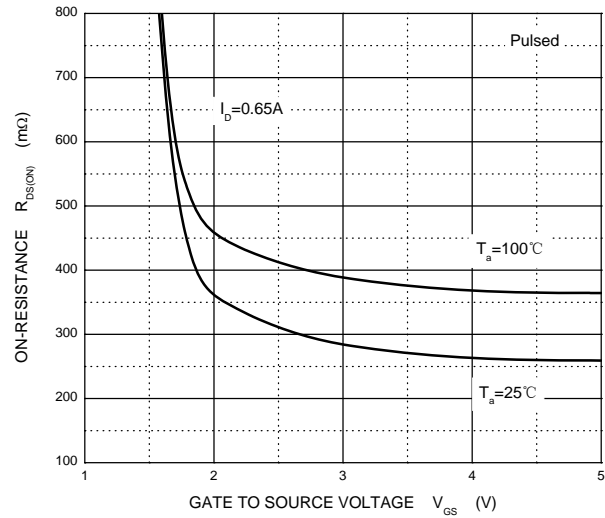
HfUbgZYf`7\UfUWhYf]ghjWg



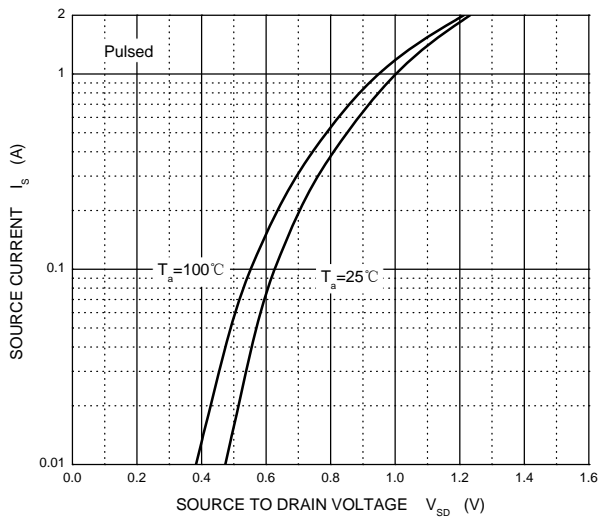
F 8GICBL i i 8



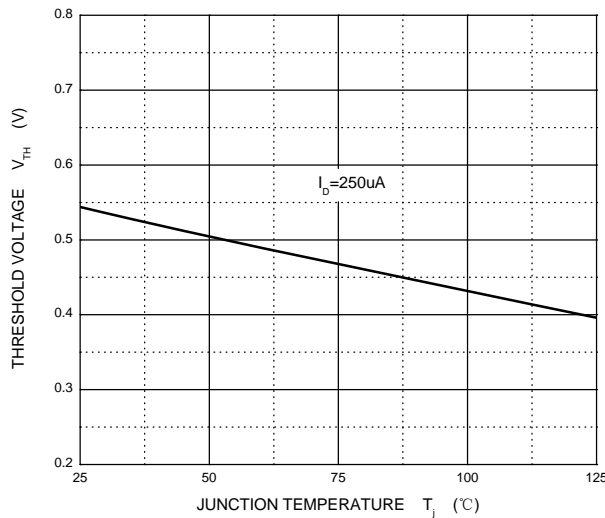
F 8GICBL i i J ; G



= i i J G8

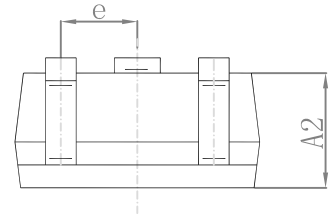
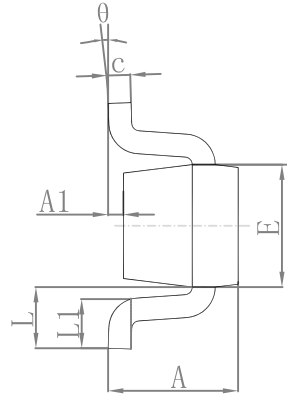
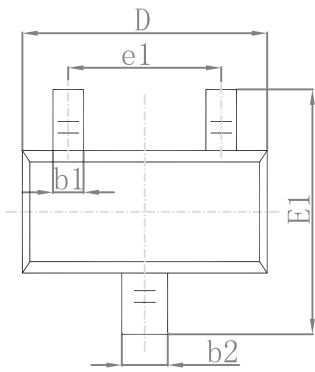


H\Yg\c`X`Jc`hUY



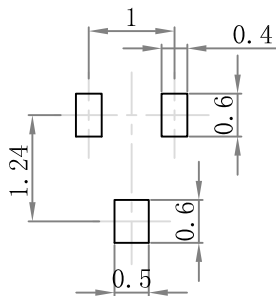
DUW_U [Y' C i h'] bY' 8] a Ybg]cbg'

GCH!)&'



Gma Vc'	8]a Ybg]cbg'-b'A'] a YhYfg		8]a Ybg]cbg'-b'bw\Yg	
	A]b'	AU1'	A]b'	AU1'
A	0.700	0.900	0.028	0.035
A1	0.000	0.100	0.000	0.004
A2	0.700	0.800	0.028	0.031
b1	0.150	0.250	0.006	0.010
b2	0.250	0.350	0.010	0.014
c	0.100	0.200	0.004	0.008
D	1.500	1.700	0.059	0.067
E	0.700	0.900	0.028	0.035
E1	1.450	1.750	0.057	0.069
e	0.500 TYP.		0.020 TYP.	
e1	0.900	1.100	0.035	0.043
L	0.400 REF.		0.016 REF.	
L1	0.260	0.460	0.010	0.018
theta	0°	8°	0°	8°

Gi [[YghYX'DUX'@Umc i h



Note:

1. Controlling dimension: in millimeters.
2. General tolerance: ±0.05mm.
3. The pad layout is for reference purposes only.